Phase-plane characterization of analog-to-digital converters

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Abstract:
A phase spectrum-based approach for determining the phase-plane error of analog-to-digital converters is proposed. The approach exploits a phase-plane error modelling based on dual-tone stimulus and phase spectrum output analysis to reduce the large amount of data required by state-of-the-art tests. Numerical and experimental results of performance characterization, comparison with a state-of-the-art procedure by Acunto et al. (2003), and noise-sensitivity analysis are presented and discussed.

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I. Introduction

In last years, more and more accurate and efficient techniques of error modeling of analog-to-digital converters (ADCs) were set up.

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